## Applicant(s)/Patent Under Application/Control No. Reexamination 10/510.977 YAMAUCHI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Thuy V. Tran 2821 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY 12-2005 Rhee, Byung Joon 345/60 US-6,975,286 B2 Α 315/169.4 10-2003 Tokunaga et al. US-6,630,796 B2 В С US-US-D US-Е US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Name Classification Country Country Code-Number-Kind Code MM-YYYY N 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

X